AMENDMENTS TO THE CLAIMS

- (currently amended) A composition suitable for use as a planarizing underlayer in a multilayer lithographic process, said composition comprising:
 - (a) a polymer containing:
 - (i) epoxy moieties,
 - (ii) saturated fused-polycyclic hydrocarbon moieties,
 - (iii) aromatic moieties, and
 - (iv) fluorine-containing moieties, and
 - (b) an acid generator.
- (previously presented) The composition of claim 1 wherein said epoxy
 moieties are pendant from acrylate monomers, said monomers forming at
 least a portion of said polymer.
- (currently amended) The composition of claim 1 wherein said fused polycyclic hydrocarbon moieties are pendant from acrylate monomers, said monomers forming at least a portion of said polymer.
- (currently amended) The composition of claim 1 wherein said fused-polycyclic hydrocarbon moieties are located in a backbone portion of said polymer.
- (original) The composition of claim 1 wherein said aromatic moieties are pendant from an ethylenic monomer, said monomer forming at least a portion of said polymer.
- 6. (original) The composition of claim 5 wherein said aromatic moieties are selected from the group consisting of phenyl and phenol.

- 7. (currently amended) The composition of claim 1 wherein said polymer contains acrylate monomers having both a fused-polycyclic hydrocarbon moiety and an epoxy moiety pendant from said monomer.
- 8. (original) The composition of claim 1 wherein said acid generator is a thermally activated acid generator.
- 9. (canceled)
- 10. (original) The composition of claim 1 wherein said composition consists essentially of components (a) and (b).
- 11. (currently amended) A lithographic structure on a substrate, said structure comprising:
 - a planarizing underlayer comprising: (a) a polymer containing:
 - (i) epoxy moieties,
 - (ii) saturated fused-polycyclic hydrocarbon moieties,
 - (iii) aromatic moieties, and an acid generator.
 - a radiation-sensitive imaging layer over said planarizing underlayer. (þ)
- 12. (canceled)
- 13. (original) The structure of claim 11 wherein said imaging layer is a silicon-containing resist.
- 14-20. (canceled)

3